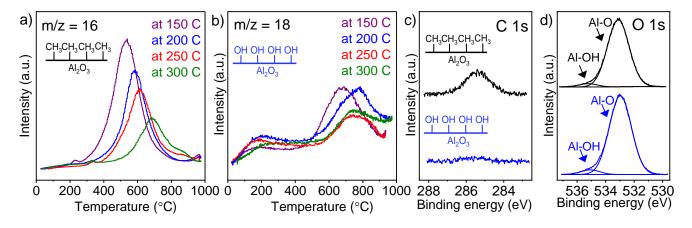


Figure 1. Schematic of the cluster tool.



**Figure 2.** TPD measurements on a) m/z = 16 after TMA pulse and b) m/z = 18 after H<sub>2</sub>O pulse from Al<sub>2</sub>O<sub>3</sub> films deposited at 150-300 °C. XPS measurements on c) C 1s and d) O 1s regions after TMA (black curves) and H<sub>2</sub>O (blue curves) pulses from Al<sub>2</sub>O<sub>3</sub> deposited at 250 °C.